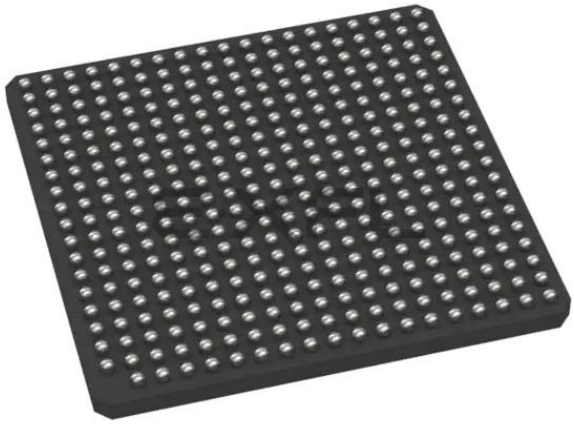

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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Active
Core Processor	PowerPC G4
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	1.0GHz
Co-Processors/DSP	Multimedia; SIMD
RAM Controllers	-
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	-
SATA	-
USB	-
Voltage - I/O	1.5V, 1.8V, 2.5V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	360-CBGA, FCCBGA
Supplier Device Package	360-FCCBGA (25x25)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=mc7448vu1000ld

  - Monitors all dispatched instructions and retires them in order
  - Tracks unresolved branches and flushes instructions after a mispredicted branch
  - Retires as many as three instructions per clock cycle
- Separate on-chip L1 instruction and data caches (Harvard architecture)
  - 32-Kbyte, eight-way set-associative instruction and data caches
  - Pseudo least-recently-used (PLRU) replacement algorithm
  - 32-byte (eight-word) L1 cache block
  - Physically indexed/physical tags
  - Cache write-back or write-through operation programmable on a per-page or per-block basis
  - Instruction cache can provide four instructions per clock cycle; data cache can provide four words per clock cycle
  - Caches can be disabled in software.
  - Caches can be locked in software.
  - MESI data cache coherency maintained in hardware
  - Separate copy of data cache tags for efficient snooping
  - Parity support on cache
  - No snooping of instruction cache except for **icbi** instruction
  - Data cache supports AltiVec LRU and transient instructions
  - Critical double- and/or quad-word forwarding is performed as needed. Critical quad-word forwarding is used for AltiVec loads and instruction fetches. Other accesses use critical double-word forwarding.
- Level 2 (L2) cache interface
  - On-chip, 1-Mbyte, eight-way set-associative unified instruction and data cache
  - Cache write-back or write-through operation programmable on a per-page or per-block basis
  - Parity support on cache tags
  - ECC or parity support on data
  - Error injection allows testing of error recovery software
- Separate memory management units (MMUs) for instructions and data
  - 52-bit virtual address, 32- or 36-bit physical address
  - Address translation for 4-Kbyte pages, variable-sized blocks, and 256-Mbyte segments
  - Memory programmable as write-back/write-through, caching-inhibited/caching-allowed, and memory coherency enforced/memory coherency not enforced on a page or block basis
  - Separate IBATs and DBATs (eight each) also defined as SPRs
  - Separate instruction and data translation lookaside buffers (TLBs)
    - Both TLBs are 128-entry, two-way set-associative and use an LRU replacement algorithm.
    - TLBs are hardware- or software-reloadable (that is, a page table search is performed in hardware or by system software on a TLB miss).

- Reliability and serviceability
  - Parity checking on system bus
  - Parity checking on the L1 caches and L2 data tags
  - ECC or parity checking on L2 data

3 Comparison with the MPC7447A, MPC7447, MPC7445, and MPC7441

Table 1 compares the key features of the MPC7448 with the key features of the earlier MPC7447A, MPC7447, MPC7445, and MPC7441. All are based on the MPC7450 RISC microprocessor and are architecturally very similar. The MPC7448 is identical to the MPC7447A, but the MPC7448 supports 1 Mbyte of L2 cache with ECC and the use of dynamic frequency switching (DFS) with more bus-to-core ratios.

Table 1. Microarchitecture Comparison

Microarchitectural Specs	MPC7448	MPC7447A	MPC7447	MPC7445	MPC7441
Basic Pipeline Functions					
Logic inversions per cycle	18				
Pipeline stages up to execute	5				
Total pipeline stages (minimum)	7				
Pipeline maximum instruction throughput	3 + branch				
Pipeline Resources					
Instruction buffer size	12				
Completion buffer size	16				
Renames (integer, float, vector)	16, 16, 16				
Maximum Execution Throughput					
SFX	3				
Vector	2 (any 2 of 4 units)				
Scalar floating-point	1				
Out-of-Order Window Size in Execution Queues					
SFX integer units	1 entry × 3 queues				
Vector units	In order, 4 queues				
Scalar floating-point unit	In order				
Branch Processing Resources					
Prediction structures	BTIC, BHT, link stack				
BTIC size, associativity	128-entry, 4-way				
BHT size	2K-entry				
Link stack depth	8				
Unresolved branches supported	3				
Branch taken penalty (BTIC hit)	1				
Minimum misprediction penalty	6				

4 General Parameters

The following list summarizes the general parameters of the MPC7448:

Technology	90 nm CMOS SOI, nine-layer metal	
Die size	8.0 mm × 7.3 mm	
Transistor count	90 million	
Logic design	Mixed static and dynamic	
Packages	Surface mount 360 ceramic ball grid array (HCTE)	
	Surface mount 360 ceramic land grid array (HCTE)	
	Surface mount 360 ceramic ball grid array with lead-free spheres (HCTE)	
Core power supply	1.30 V	(1700 MHz device)
	1.25 V	(1600 MHz device)
	1.20 V	(1420 MHz device)
	1.15 V	(1000 MHz device)
I/O power supply	1.5 V, 1.8 V, or 2.5 V	

5 Electrical and Thermal Characteristics

This section provides the AC and DC electrical specifications and thermal characteristics for the MPC7448.

5.1 DC Electrical Characteristics

The tables in this section describe the MPC7448 DC electrical characteristics. Table 2 provides the absolute maximum ratings. See Section 9.2, “Power Supply Design and Sequencing,” for power sequencing requirements.

Table 2. Absolute Maximum Ratings [1]

Characteristic		Symbol	Maximum Value	Unit	Notes
Core supply voltage		V_{DD}	–0.3 to 1.4	V	2
PLL supply voltage		AV_{DD}	–0.3 to 1.4	V	2
Processor bus supply voltage	I/O Voltage Mode = 1.5 V	OV_{DD}	–0.3 to 1.8	V	3
	I/O Voltage Mode = 1.8 V		–0.3 to 2.2		3
	I/O Voltage Mode = 2.5 V		–0.3 to 3.0		3
Input voltage	Processor bus	V_{in}	–0.3 to OV_{DD} + 0.3	V	4
	JTAG signals	V_{in}	–0.3 to OV_{DD} + 0.3	V	
Storage temperature range		T_{stg}	– 55 to 150	•C	

Notes:

1. Functional and tested operating conditions are given in Table 4. Absolute maximum ratings are stress ratings only and functional operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage to the device.
2. See Section 9.2, “Power Supply Design and Sequencing” for power sequencing requirements.
3. Bus must be configured in the corresponding I/O voltage mode; see Table 3.
4. **Caution**: V_{in} must not exceed OV_{DD} by more than 0.3 V at any time including during power-on reset except as allowed by the overshoot specifications. V_{in} may overshoot/undershoot to a voltage and for a maximum duration as shown in Figure 2.

Figure 2 shows the undershoot and overshoot voltage on the MPC7448.

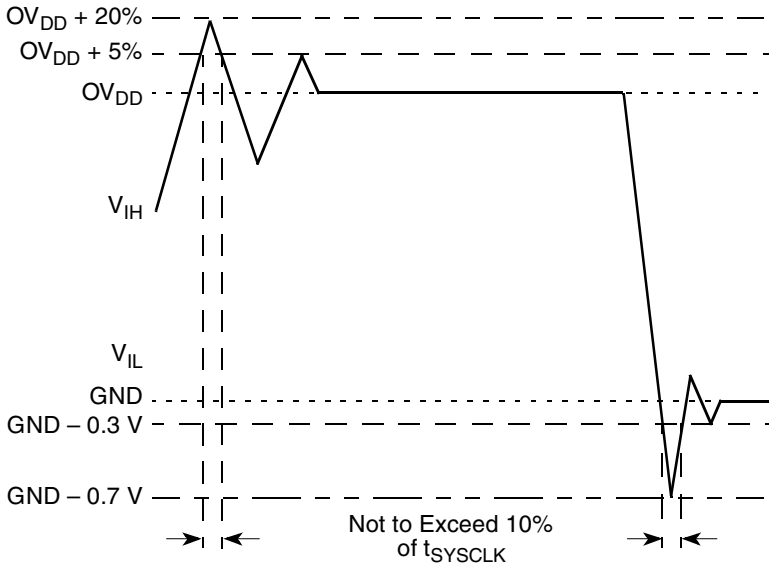

Figure 2. Overshoot/Undershoot Voltage

The MPC7448 provides several I/O voltages to support both compatibility with existing systems and migration to future systems. The MPC7448 core voltage must always be provided at the nominal voltage (see Table 4). The input voltage threshold for each bus is selected by sampling the state of the voltage select pins at the negation of the signal $\overline{\text{HRESET}}$. The output voltage will swing from GND to the maximum voltage applied to the OV_{DD} power pins. Table 3 provides the input threshold voltage settings. Because these settings may change in future products, it is recommended that BVSEL[0:1] be configured using resistor options, jumpers, or some other flexible means, with the capability to reconfigure the termination of this signal in the future, if necessary.

Table 3. Input Threshold Voltage Setting

BVSEL0	BVSEL1	I/O Voltage Mode[1]	Notes
0	0	1.8 V	2, 3
0	1	2.5 V	2, 4
1	0	1.5 V	2
1	1	2.5 V	4

Notes:

1. **Caution:** The I/O voltage mode selected must agree with the OV_{DD} voltages supplied. See Table 4.
2. If used, pull-down resistors should be less than 250 Ω.
3. The pin configuration used to select 1.8V mode on the MPC7448 is not compatible with the pin configuration used to select 1.8V mode on the MPC7447A and earlier devices.
4. The pin configuration used to select 2.5V mode on the MPC7448 is fully compatible with the pin configuration used to select 2.5V mode on the MPC7447A and earlier devices.

Table 4 provides the recommended operating conditions for the MPC7448 part numbers described by this document; see Section 11.1, “Part Numbers Fully Addressed by This Document,” for more information. See Section 9.2, “Power Supply Design and Sequencing” for power sequencing requirements.

Table 4. Recommended Operating Conditions[1]

Characteristic		Symbol	Recommended Value								Unit	Notes
			1000 MHz		1420 MHz		1600 MHz		1700 MHz			
			Min	Max	Min	Max	Min	Max	Min	Max		
Core supply voltage		V_{DD}	1.15 V ± 50 mV		1.2 V ± 50 mV		1.25 V ± 50 mV		1.3 V +20/ – 50 mV		V	3, 4, 5
PLL supply voltage		AV_{DD}	1.15 V ± 50 mV		1.2 V ± 50 mV		1.25 V ± 50 mV		1.3 V +20/ – 50 mV		V	2, 3, 4
Processor bus supply voltage	I/O Voltage Mode = 1.5 V	OV_{DD}	1.5 V ± 5%		1.5 V ± 5%		1.5 V ± 5%		1.5 V ± 5%		V	4
	I/O Voltage Mode = 1.8 V		1.8 V ± 5%		1.8 V ± 5%		1.8 V ± 5%		1.8 V ± 5%			4
	I/O Voltage Mode = 2.5 V		2.5 V ± 5%		2.5 V ± 5%		2.5 V ± 5%		2.5 V ± 5%			4
Input voltage	Processor bus	V_{in}	GND	OV_{DD}	GND	OV_{DD}	GND	OV_{DD}	GND	OV_{DD}	V	
	JTAG signals	V_{in}	GND	OV_{DD}	GND	OV_{DD}	GND	OV_{DD}	GND	OV_{DD}		
Die-junction temperature		T_j	0	105	0	105	0	105	0	105	•C	6

Notes:

1. These are the recommended and tested operating conditions.
2. This voltage is the input to the filter discussed in Section 9.2.2, “PLL Power Supply Filtering,” and not necessarily the voltage at the AV_{DD} pin, which may be reduced from V_{DD} by the filter.
3. Some early devices supported voltage and frequency derating whereby VDD (and AVDD) could be reduced to reduce power consumption. This feature has been superseded and is no longer supported. See Section 5.3, “Voltage and Frequency Derating,” for more information.
4. **Caution**: Power sequencing requirements must be met; see Section 9.2, “Power Supply Design and Sequencing”.
5. **Caution**: See Section 9.2.3, “Transient Specifications” for information regarding transients on this power supply.
6. For information on extended temperature devices, see Section 11.2, “Part Numbers Not Fully Addressed by This Document.”

5.2 AC Electrical Characteristics

This section provides the AC electrical characteristics for the MPC7448. After fabrication, functional parts are sorted by maximum processor core frequency as shown in Section 5.2.1, “Clock AC Specifications,” and tested for conformance to the AC specifications for that frequency. The processor core frequency, determined by the bus (SYSCLK) frequency and the settings of the PLL_CFG[0:5] signals, can be dynamically modified using dynamic frequency switching (DFS). Parts are sold by maximum processor core frequency; see Section 11, “Part Numbering and Marking,” for information on ordering parts. DFS is described in Section 9.7.5, “Dynamic Frequency Switching (DFS).”

5.2.1 Clock AC Specifications

Table 8 provides the clock AC timing specifications as defined in Figure 3 and represents the tested operating frequencies of the devices. The maximum system bus frequency, f_{SYSCLK}, given in Table 8, is considered a practical maximum in a typical single-processor system. This does not exclude multi-processor systems, but these typically require considerably more design effort to achieve the maximum rated bus frequency. The actual maximum SYSCLK frequency for any application of the MPC7448 will be a function of the AC timings of the microprocessor(s), the AC timings for the system controller, bus loading, circuit board topology, trace lengths, and so forth, and may be less than the value given in Table 8.

Table 8. Clock AC Timing Specifications

At recommended operating conditions. See Table 4.

Characteristic		Symbol	Maximum Processor Core Frequency (Speed Grade)								Unit	Notes
			1000 MHz		1420 MHz		1600 MHz		1700 MHz			
			Min	Max	Min	Max	Min	Max	Min	Max		
Processor core frequency	DFS mode disabled	f_{core}	600	1000	600	1420	600	1600	600	1700	MHz	1, 8
	DFS mode enabled	f_{core_DF}	300	500	300	710	300	800	300	850		9
VCO frequency		f_{VCO}	600	1000	600	1420	600	800	600	1700	MHz	1, 10
SYSCLK frequency		f_{SYSCLK}	33	200	33	200	33	200	33	200	MHz	1, 2, 8
SYSCLK cycle time		t_{SYSCLK}	5.0	30	5.0	30	5.0	30	5.0	30	ns	2
SYSCLK rise and fall time		t_{KR}, t_{KF}	—	0.5	—	0.5	—	0.5	—	0.5	ns	3
SYSCLK duty cycle measured at $OV_{DD}/2$		t_{KHKL}/t_{SYSCLK}	40	60	40	60	40	60	40	60	%	4
SYSCLK cycle-to-cycle jitter			—	150	—	150	—	150	—	150	ps	5, 6
Internal PLL relock time			—	100	—	100	—	100	—	100	µs	7

Notes:

1. **Caution**: The SYSCLK frequency and PLL_CFG[0:5] settings must be chosen such that the resulting SYSCLK (bus) frequency, processor core frequency, and PLL (VCO) frequency do not exceed their respective maximum or minimum operating frequencies. Refer to the PLL_CFG[0:5] signal description in Section 9.1.1, “PLL Configuration,” for valid PLL_CFG[0:5] settings.
2. Actual maximum system bus frequency is system-dependent. See Section 5.2.1, “Clock AC Specifications.”
3. Rise and fall times for the SYSCLK input measured from 0.4 to 1.4 V
4. Timing is guaranteed by design and characterization.
5. Guaranteed by design
6. The SYSCLK driver’s closed loop jitter bandwidth should be less than 1.5 MHz at –3 dB.
7. Relock timing is guaranteed by design and characterization. PLL-relock time is the maximum amount of time required for PLL lock after a stable V_{DD} and SYSCLK are reached during the power-on reset sequence. This specification also applies when the PLL has been disabled and subsequently re-enabled during sleep mode. Also note that $\overline{\text{HRESET}}$ must be held asserted for a minimum of 255 bus clocks after the PLL-relock time during the power-on reset sequence.
8. This reflects the maximum and minimum core frequencies when the dynamic frequency switching feature (DFS) is disabled. f_{core_DFS} provides the maximum and minimum core frequencies when operating in a DFS mode.
9. This specification supports the Dynamic Frequency Switching (DFS) feature and is applicable only when one of the DFS modes (divide-by-2 or divide-by-4) is enabled. When DFS is disabled, the core frequency must conform to the maximum and minimum frequencies stated for f_{core}.
10. Use of the DFS feature does not affect VCO frequency.

Figure 3 provides the SYSCLK input timing diagram.

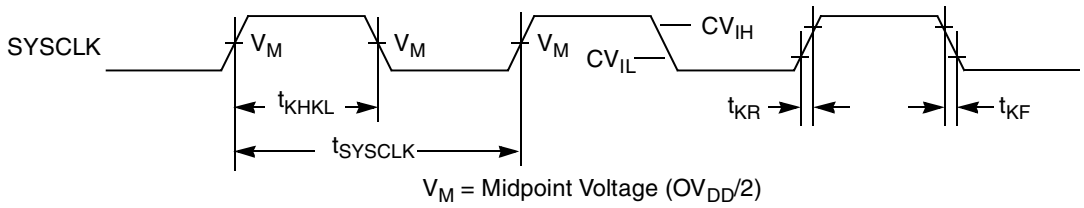

Figure 3. SYSCLK Input Timing Diagram

5.2.2 Processor Bus AC Specifications

Table 9 provides the processor bus AC timing specifications for the MPC7448 as defined in Figure 4 and Figure 5.

Table 9. Processor Bus AC Timing Specifications[1]

At recommended operating conditions. See Table 4.

Parameter	Symbol [2]	All Speed Grades		Unit	Notes
		Min	Max		
Input setup times:				ns	
A[0:35], AP[0:4]	t_{AVKH}	1.5	—		—
D[0:63], DP[0:7]	t_{DVKH}	1.5	—		—
AACK, ARTRY, BG, CKSTP_IN, DBG, DTI[0:3], GBL, TT[0:4], QACK, TA, TBEN, TEA, TS, EXT_QUAL, PMON_IN, SHD[0:1]	t_{IVKH}	1.5	—		—
BMODE[0:1], BVSEL[0:1]	t_{MVKH}	1.5	—		8
Input hold times:				ns	
A[0:35], AP[0:4]	t_{AXKH}	0	—		—
D[0:63], DP[0:7]	t_{DXKH}	0	—		—
AACK, ARTRY, BG, CKSTP_IN, DBG, DTI[0:3], GBL, TT[0:4], QACK, TA, TBEN, TEA, TS, EXT_QUAL, PMON_IN, SHD[0:1]	t_{IXKH}	0	—		—
					—
BMODE[0:1], BVSEL[0:1]	t_{MXKH}	0	—		8
Output valid times:				ns	
A[0:35], AP[0:4]	t_{KHAV}	—	1.8		
D[0:63], DP[0:7]	t_{KHDV}	—	1.8		
BR, CI, DRDY, GBL, HIT, PMON_OUT, QREQ, TBST, TSIZ[0:2], TT[0:4], WT	t_{KHOV}	—	1.8		
TS	t_{KHTSV}	—	1.8		
ARTRY, SHD[0:1]	t_{KHARV}	—	1.8		
Output hold times:				ns	
A[0:35], AP[0:4]	t_{KHAX}	0.5	—		
D[0:63], DP[0:7]	t_{KHDX}	0.5	—		
BR, CI, DRDY, GBL, HIT, PMON_OUT, QREQ, TBST, TSIZ[0:2], TT[0:4], WT	t_{KHOX}	0.5	—		
TS	t_{KHTSX}	0.5	—		
ARTRY, SHD[0:1]	t_{KHARX}	0.5	—		
SYSCLK to output enable	t_{KHOE}	0.5	—	ns	5

Figure 4 provides the AC test load for the MPC7448.

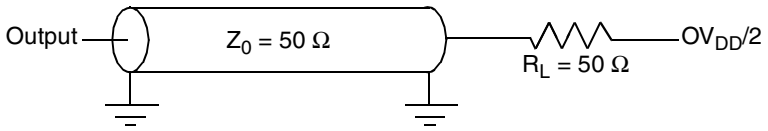

Figure 4. AC Test Load

Figure 5 provides the $\overline{\text{BMODE}}$[0:1] input timing diagram for the MPC7448. These mode select inputs are sampled once before and once after $\overline{\text{HRESET}}$ negation.

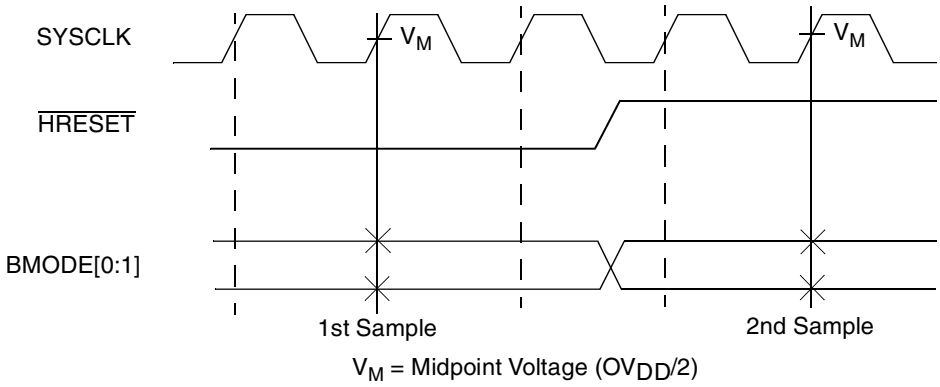

Figure 5. $\overline{\text{BMODE}}$[0:1] Input Sample Timing Diagram

Figure 6 provides the input/output timing diagram for the MPC7448.

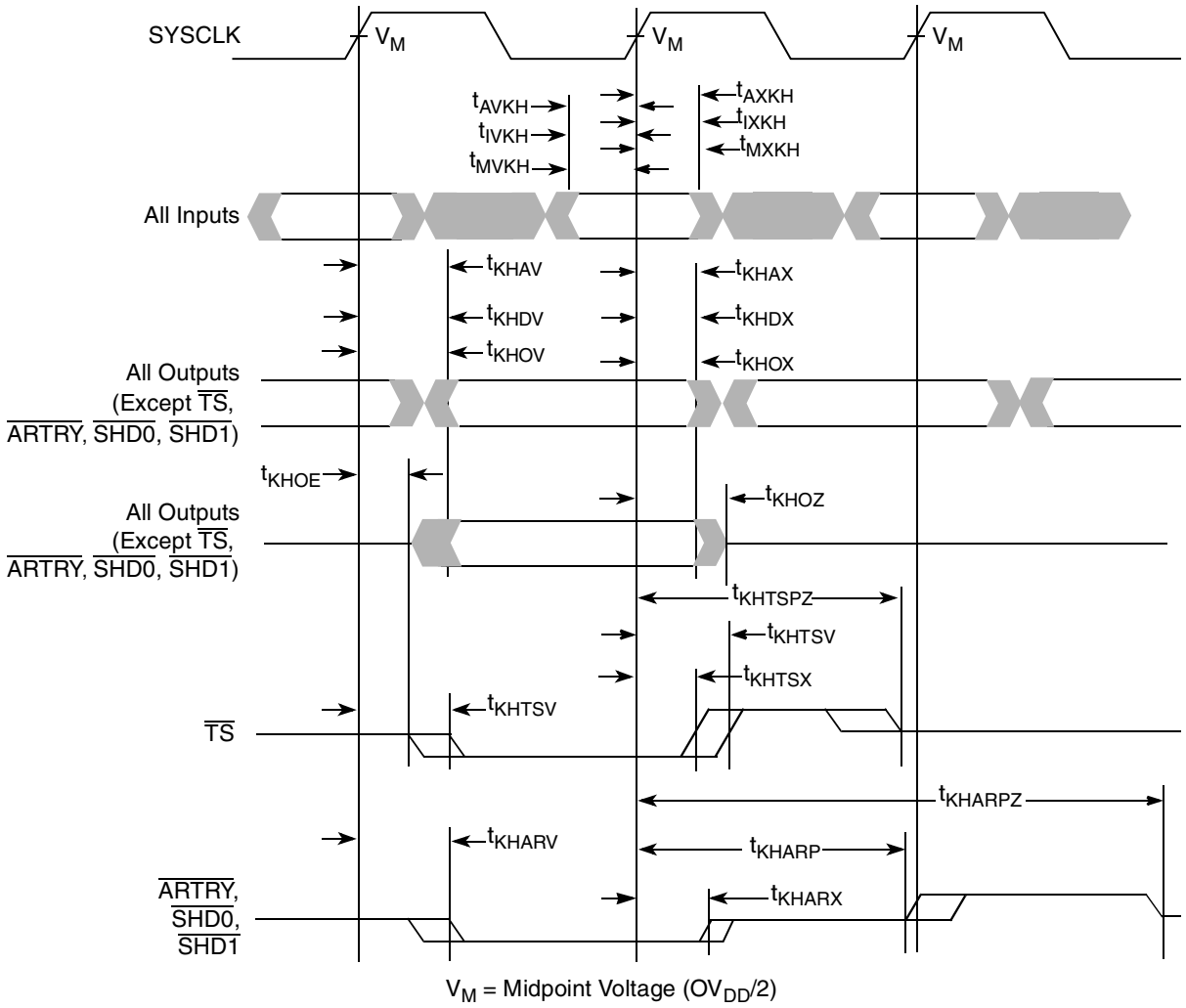

Figure 6. Input/Output Timing Diagram

5.2.3 IEEE Std. 1149.1 AC Timing Specifications

Table 10 provides the IEEE Std. 1149.1 (JTAG) AC timing specifications as defined in Figure 8 through Figure 11.

Table 10. JTAG AC Timing Specifications (Independent of SYSCLK)[1]

At recommended operating conditions. See Table 4.

Parameter	Symbol	Min	Max	Unit	Notes
TCK frequency of operation	f_{TCLK}	0	33.3	MHz	
TCK cycle time	t_{TCLK}	30	—	ns	
TCK clock pulse width measured at 1.4 V	t_{JHJL}	15	—	ns	
TCK rise and fall times	t_{JR} and t_{JF}	—	2	ns	
$\overline{\text{TRST}}$ assert time	t_{TRST}	25	—	ns	2
Input setup times: Boundary-scan data TMS, TDI	 t_{DVJH} t_{IVJH}	 4 0	 — —	ns	3
Input hold times: Boundary-scan data TMS, TDI	 t_{DXJH} t_{IXJH}	 20 25	 — —	ns	3
Valid times: Boundary-scan data TDO	 t_{JLDV} t_{JLOV}	 4 4	 20 25	ns	4
Output hold times: Boundary-scan data TDO	 t_{JLDX} t_{JLOX}	 30 30	 — —	ns	4
TCK to output high impedance: Boundary-scan data TDO	 t_{JLDZ} t_{JLOZ}	 3 3	 19 9	ns	4, 5

Notes:

1. All outputs are measured from the midpoint voltage of the falling/rising edge of TCLK to the midpoint of the signal in question. The output timings are measured at the pins. All output timings assume a purely resistive 50-Ω load (see Figure 7). Time-of-flight delays must be added for trace lengths, vias, and connectors in the system.
2. $\overline{\text{TRST}}$ is an asynchronous level sensitive signal. The time is for test purposes only.
3. Non-JTAG signal input timing with respect to TCK.
4. Non-JTAG signal output timing with respect to TCK.
5. Guaranteed by design and characterization.

Figure 11 provides the test access port timing diagram.

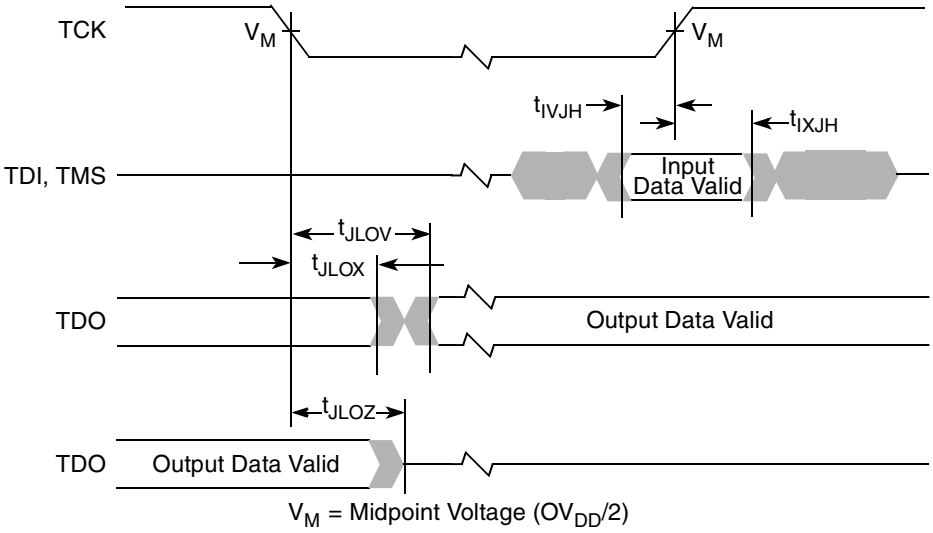

Figure 11. Test Access Port Timing Diagram

5.3 Voltage and Frequency Derating

Voltage and frequency derating is no longer supported for part numbers described by this document beginning with datecode 0613. (See Section 11, “Part Numbering and Marking,” for information on date code markings.) It is supported by some MPC7448 part numbers which target low-power applications; see Section 11.2, “Part Numbers Not Fully Addressed by This Document” and the referenced MPC7448 Hardware Specification Addenda for more information on these low-power devices. For those devices which previously supported this feature, information has been archived in the *Chip Errata for the MPC7448* (document order no. MPC7448CE).

7 Pinout Listings

Table 11 provides the pinout listing for the MPC7448, 360 HCTE package. The pinouts of the MPC7448 and MPC7447A are compatible, but the requirements regarding the use of the additional power and ground pins have changed. The MPC7448 requires these pins be connected to the appropriate power or ground plane to achieve high core frequencies; see Section 9.3, “Connection Recommendations,” for additional information. As a result, these pins should be connected in all new designs.

Additionally, the MPC7448 may be populated on a board designed for a MPC7447 (or MPC7445 or MPC7441), provided the core voltage can be made to match the requirements in Table 4 and all pins defined as ‘no connect’ for the MPC7447 are unterminated, as required by the *MPC7457 RISC Microprocessor Hardware Specifications*. The MPC7448 uses pins previously marked ‘no connect’ for the temperature diode pins and for additional power and ground connections. The additional power and ground pins are required to achieve high core frequencies and core frequency will be limited if they are not connected; see Section 9.3, “Connection Recommendations,” for additional information. Because these ‘no connect’ pins in the MPC7447 360 pin package are not driven in functional mode, an MPC7447 can be populated in an MPC7448 board.

NOTE

Caution must be exercised when performing boundary scan test operations on a board designed for an MPC7448, but populated with an MPC7447 or earlier device. This is because in the MPC7447 it is possible to drive the latches associated with the former ‘no connect’ pins in the MPC7447, potentially causing contention on those pins. To prevent this, ensure that these pins are not connected on the board or, if they are connected, ensure that the states of internal MPC7447 latches do not cause these pins to be driven during board testing.

For the MPC7448, pins that were defined as the TEST[0:4] factory test signal group on the MPC7447A and earlier devices have been assigned new functions. For most of these, the termination recommendations for the TEST[0:4] pins of the MPC7447A are compatible with the MPC7448 and will allow correct operation with no performance loss. The exception is BVSEL1 (TEST3 on the MPC7447A and earlier devices), which may require a different termination depending which I/O voltage mode is desired; see Table 3 for more information.

NOTE

This pinout is not compatible with the MPC750, MPC7400, or MPC7410 360 BGA package.

Table 11. Pinout Listing for the MPC7448, 360 HCTE Package (continued)

Signal Name	Pin Number	Active	I/O	Notes
$\overline{\text{LVRAM}}$	B10	—	—	12, 20, 22
NC (no connect)	A6, A14, A15, B14, B15, C14, C15, C16, C17, C18, C19, D14, D15, D16, D17, D18, D19, E14, E15, F14, F15, G14, G15, H15, H16, J15, J16, J17, J18, J19, K15, K16, K17, K18, K19, L15, L16, L17, L18, L19	—	—	11
$\overline{\text{LSSD\_MODE}}$	E8	Low	Input	6, 12
$\overline{\text{MCP}}$	C9	Low	Input	
OV_{DD}	B4, C2, C12, D5, F2, H3, J5, K2, L5, M3, N6, P2, P8, P11, R4, R13, R16, T6, T9, U2, U12, U16, V4, V7, V10, V14	—	—	
OVDD_SENSE	E18, G18	—	—	16
PLL_CFG[0:4]	B8, C8, C7, D7, A7	High	Input	
PLL_CFG[5]	D10	High	Input	9, 20
$\overline{\text{PMON\_IN}}$	D9	Low	Input	13
$\overline{\text{PMON\_OUT}}$	A9	Low	Output	
$\overline{\text{QACK}}$	G5	Low	Input	
$\overline{\text{QREQ}}$	P4	Low	Output	
$\overline{\text{SHD}}$[0:1]	E4, H5	Low	I/O	3
$\overline{\text{SMI}}$	F9	Low	Input	
$\overline{\text{SRESET}}$	A2	Low	Input	
SYSCLK	A10	—	Input	
$\overline{\text{TA}}$	K6	Low	Input	
TBEN	E1	High	Input	
$\overline{\text{TBST}}$	F11	Low	Output	
TCK	C6	High	Input	
TDI	B9	High	Input	6
TDO	A4	High	Output	
$\overline{\text{TEA}}$	L1	Low	Input	
TEMP_ANODE	N18	—	—	17
TEMP_CATHODE	N19	—	—	17
TMS	F1	High	Input	6
$\overline{\text{TRST}}$	A5	Low	Input	6, 14
$\overline{\text{TS}}$	L4	Low	I/O	3
TSIZ[0:2]	G6, F7, E7	High	Output	
TT[0:4]	E5, E6, F6, E9, C5	High	I/O	
$\overline{\text{WT}}$	D3	Low	Output	
V_{DD}	H8, H10, H12, J7, J9, J11, J13, K8, K10, K12, K14, L7, L9, L11, L13, M8, M10, M12	—	—	
V_{DD}	A13, A16, A18, B17, B19, C13, E13, E16, F12, F17, F19, G11, G16, H14, H17, H19, M14, M16, M18, N15, N17, P16, P18	—	—	15

Table 11. Pinout Listing for the MPC7448, 360 HCTE Package (continued)

Signal Name	Pin Number	Active	I/O	Notes
VDD_SENSE	G13, N12	—	—	18

Notes:

1. OV_{DD} supplies power to the processor bus, JTAG, and all control signals, and is configurable. (V_{DD} supplies power to the processor core, and AV_{DD} supplies power to the PLL after filtering from V_{DD}). To program the I/O voltage, see Table 3. If used, the pull-down resistor should be less than 250 Ω. Because these settings may change in future products, it is recommended BVSEL[0:1] be configured using resistor options, jumpers, or some other flexible means, with the capability to reconfigure the termination of this signal in the future if necessary. For actual recommended value of V_{in} or supply voltages see Table 4.
2. Unused address pins must be pulled down to GND and corresponding address parity pins pulled up to OV_{DD}.
3. These pins require weak pull-up resistors (for example, 4.7 KΩ) to maintain the control signals in the negated state after they have been actively negated and released by the MPC7448 and other bus masters.
4. This signal selects between MPX bus mode (asserted) and 60x bus mode (negated) and will be sampled at $\overline{\text{HRESET}}$ going high.
5. This signal must be negated during reset, by pull-up resistor to OV_{DD} or negation by ¬$\overline{\text{HRESET}}$ (inverse of $\overline{\text{HRESET}}$), to ensure proper operation.
6. Internal pull up on die.
7. Not used in 60x bus mode.
8. These signals must be pulled down to GND if unused, or if the MPC7448 is in 60x bus mode.
9. These input signals are for factory use only and must be pulled down to GND for normal machine operation.
10. This test signal is recommended to be tied to $\overline{\text{HRESET}}$; however, other configurations will not adversely affect performance.
11. These signals are for factory use only and must be left unconnected for normal machine operation. Some pins that were NCs on the MPC7447, MPC7445, and MPC7441 have now been defined for other purposes.
12. These input signals are for factory use only and must be pulled up to OV_{DD} for normal machine operation.
13. This pin can externally cause a performance monitor event. Counting of the event is enabled through software.
14. This signal must be asserted during reset, by pull down to GND or assertion by $\overline{\text{HRESET}}$, to ensure proper operation.
15. These pins were NCs on the MPC7447, MPC7445, and MPC7441. See Section 9.3, “Connection Recommendations,” for more information.
16. These pins were OV_{DD} pins on the MPC7447, MPC7445, and MPC7441. These pins are internally connected to OV_{DD} and are intended to allow an external device (such as a power supply) to detect the I/O voltage level present inside the device package. If unused, it is recommended they be connected to test points to facilitate system debug; otherwise, they may be connected directly to OV_{DD} or left unconnected.
17. These pins provide connectivity to the on-chip temperature diode that can be used to determine the die junction temperature of the processor. These pins may be left unterminated if unused.
18. These pins are internally connected to V_{DD} and are intended to allow an external device (such as a power supply) to detect the processor core voltage level present inside the device package. If unused, it is recommended they be connected to test points to facilitate system debug; otherwise, they may be connected directly to V_{DD} or left unconnected.
19. These pins are internally connected to GND and are intended to allow an external device to detect the processor ground voltage level present inside the device package. If unused, it is recommended they be connected to test points to facilitate system debug; otherwise, they may be connected directly to GND or left unconnected.
20. These pins were in the TEST[0:4] factory test pin group on the MPC7447A, MPC7447, MPC7445, and MPC7441. They have been assigned new functions on the MPC7448.
21. These pins can be used to enable the supported dynamic frequency switching (DFS) modes via hardware. If both are pulled down, DFS mode is disabled completely and cannot be enabled via software. If unused, they should be pulled up to OV_{DD} to allow software control of DFS. See the *MPC7450 RISC Microprocessor Family Reference Manual* for more information.
22. This pin is provided to allow operation of the L2 cache at low core voltages and is for factory use only. See the *MPC7450 RISC Microprocessor Family Reference Manual* for more information.

9.2.3 Transient Specifications

The ensure the long-term reliability of the device, the MPC7448 requires that transients on the core power rail (V_{DD}) be constrained. The recommended operating voltage specifications provided in Table 4 are DC specifications. That is, the device may be operated continuously with V_{DD} within the specified range without adversely affecting the device's reliability. Excursions above the stated recommended operation range, including overshoot during power-up, can impact the long-term reliability of the device. Excursions are described by their amplitude and duration. Duration is defined as the time period during which the V_{DD} power plane, as measured at the VDD_SENSE pins, will be within a specific voltage range, expressed as percentage of the total time the device will be powered up over the device lifetime. In practice, the period over which transients are measured can be any arbitrary period of time that accurately represents the expected range of processor and system activity. The voltage ranges and durations for normal operation and transients are described in Table 14.

Table 14. VDD Power Supply Transient Specifications

At recommended operating temperatures. See Table 4.

Voltage Region	Voltage Range (V)		Permitted Duration [1]	Notes
	Min	Max		
Normal	V_{DD} minimum	V_{DD} maximum	100%	2
Low Transient	V_{DD} maximum	1.35 V	10%	2, 3
High Transient	1.35 V	1.40 V	0.2%	4

Notes:
1. Permitted duration is defined as the percentage of the total time the device is powered on that the V_{DD} power supply voltage may exist within the specified voltage range.
2. See Table 4 for nominal V_{DD} specifications.
3. To simplify measurement, excursions into the High Transient region are included in this duration.
4. Excursions above the absolute maximum rating of 1.4 V are not permitted; see Table 2.

Note that, to simplify transient measurements, the duration of the excursion into the High Transient region is also included in the Low Transient duration, so that only the time the voltage is above each threshold must be considered. Figure 19 shows an example of measuring voltage transients.

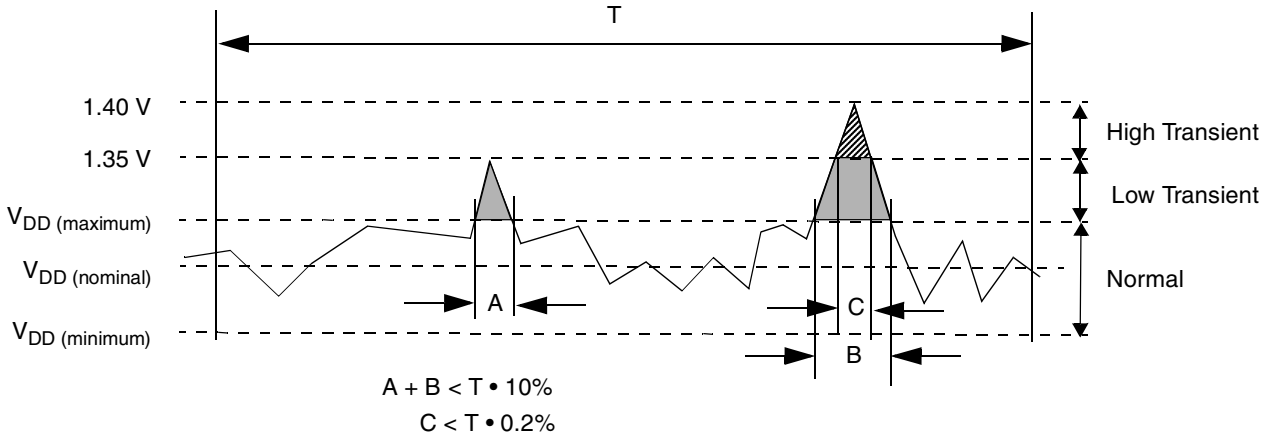

Figure 19. Voltage Transient Example

Due to the complexity and variety of system-level boundary conditions for today's microelectronic equipment, the combined effects of the heat transfer mechanisms (radiation, convection, and conduction) may vary widely. For these reasons, we recommend using conjugate heat transfer models for the board as well as system-level designs.

For system thermal modeling, the MPC7448 thermal model is shown in Figure 26. Four volumes represent this device. Two of the volumes, solder ball-air and substrate, are modeled using the package outline size of the package. The other two, die and bump-underfill, have the same size as the die. The silicon die should be modeled $8.0 \times 7.3 \times 0.86$ mm^3 with the heat source applied as a uniform source at the bottom of the volume. The bump and underfill layer is modeled as $8.0 \times 7.3 \times 0.07$ mm^{3}collapsed in the z-direction with a thermal conductivity of 5.0 W/(m • K) in the z-direction. The substrate volume is $25 \times 25 \times 1.14$ mm^3 and has 9.9 W/(m • K) isotropic conductivity in the xy-plane and 2.95 W/(m • K) in the direction of the z-axis. The solder ball and air layer are modeled with the same horizontal dimensions as the substrate and is 0.8 mm thick. For the LGA package the solder and air layer is 0.1 mm thick, but the material properties are the same. It can also be modeled as a collapsed volume using orthotropic material properties: 0.034 W/(m • K) in the xy-plane direction and 11.2 W/(m • K) in the direction of the z-axis.

Conductivity	Value	Unit
Die ($8.0 \times 7.3 \times 0.86$ mm^3)		
Silicon	Temperature-dependent	W/(m • K)
Bump and Underfill ($8.0 \times 7.3 \times 0.07$ mm^3)		
k_z	5.0	W/(m • K)
Substrate ($25 \times 25 \times 1.14$ mm^3)		
k_x	9.9	W/(m • K)
k_y	9.9	
k_z	2.95	
Solder Ball and Air ($25 \times 25 \times 0.8$ mm^3)		
k_x	0.034	W/(m • K)
k_y	0.034	
k_z	11.2	

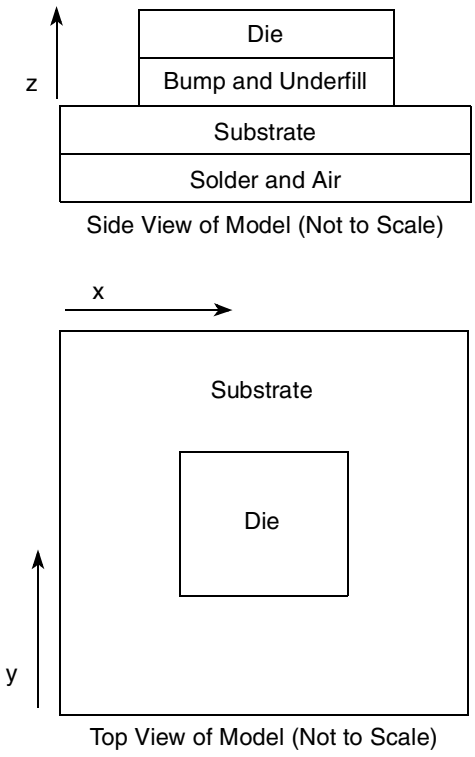

Figure 26. Recommended Thermal Model of MPC7448

9.7.4 Temperature Diode

The MPC7448 has a temperature diode on the microprocessor that can be used in conjunction with other system temperature monitoring devices (such as Analog Devices, ADT7461™). These devices use the negative temperature coefficient of a diode operated at a constant current to determine the temperature of the microprocessor and its environment. For proper operation, the monitoring device used should auto-calibrate the device by canceling out the V_{BE} variation of each MPC7448's internal diode.

The following are the specifications of the MPC7448 on-board temperature diode:

$V_f > 0.40$ V

$V_f < 0.90$ V

Operating range 2–300 µA

Diode leakage < 10 nA @ 125°C

Ideality factor over 5–150 µA at 60°C: n = 1.0275 ± 0.9%

Ideality factor is defined as the deviation from the ideal diode equation:

$$I_{fw} = I_s \left[e^{\frac{qV_f}{nKT}} - 1 \right]$$

Another useful equation is:

$$V_H - V_L = n\frac{KT}{q}\left[ln\frac{I_H}{I_L} \right] - 1$$

Where:

I_{fw} = Forward current
I_s = Saturation current
V_d = Voltage at diode
V_f = Voltage forward biased
V_H = Diode voltage while I_H is flowing
V_L = Diode voltage while I_L is flowing
I_H = Larger diode bias current
I_L = Smaller diode bias current
q = Charge of electron (1.6×10^{-19} C)
n = Ideality factor (normally 1.0)
K = Boltzman's constant (1.38×10^{-23} Joules/K)
T = Temperature (Kelvins)

The ratio of I_H to I_L is usually selected to be 10:1. The previous equation simplifies to the following:

$$V_H - V_L = 1.986 \times 10^{-4} \times nT$$

Solving for T, the equation becomes:

$$nT = \frac{V_H - V_L}{1.986 \times 10^{-4}}$$

9.7.5 Dynamic Frequency Switching (DFS)

The DFS feature in the MPC7448 adds the ability to divide the processor-to-system bus ratio by two or four during normal functional operation. Divide-by-two mode is enabled by setting the HID1[DFS2] bit in software or by asserting the $\overline{\text{DFS2}}$ pin via hardware. The MPC7448 can be returned for full speed by clearing HID1[DFS2] or negating $\overline{\text{DFS2}}$. Similarly, divide-by-four mode is enabled by setting HID1[DFS4] in software or by asserting the $\overline{\text{DFS4}}$ pin. In all cases, the frequency change occurs in 1 clock cycle and no idle waiting period is required to switch between modes. Note that asserting either $\overline{\text{DFS2}}$ or $\overline{\text{DFS4}}$ overrides software control of DFS, and that asserting both $\overline{\text{DFS2}}$ and $\overline{\text{DFS4}}$ disables DFS completely, including software control. Additional information regarding DFS can be found in the *MPC7450 RISC Microprocessor Family Reference Manual.* Note that minimum core frequency requirements must be observed when enabling DFS, and the resulting core frequency must meet the requirements for f_{core_DFS} given in Table 8.

9.7.5.1 Power Consumption with DFS Enabled

Power consumption with DFS enabled can be approximated using the following formula:

$$P_{DFS} = \left[\frac{f_{DFS}}{f}\ (P - P_{DS})\right] + P_{DS}$$

Where:

P_{DFS} = Power consumption with DFS enabled
f_{DFS} = Core frequency with DFS enabled
f = Core frequency prior to enabling DFS
P = Power consumption prior to enabling DFS (see Table 7)
P_{DS} = Deep sleep mode power consumption (see Table 7)

The above is an approximation only. Power consumption with DFS enabled is not tested or guaranteed.

9.7.5.2 Bus-to-Core Multiplier Constraints with DFS

DFS is not available for all bus-to-core multipliers as configured by PLL_CFG[0:5] during hard reset. The complete listing is shown in Table 16. Shaded cells represent DFS modes that are not available for a particular PLL_CFG[0:5] setting. Should software or hardware attempt to transition to a multiplier that is not supported, the device will remain at its current multiplier. For example, if a transition from DFS-disabled to an unsupported divide-by-2 or divide-by-4 setting is attempted, the bus-to-core multiplier will remain at the setting configured by the PLL_CFG[0:5] pins. In the case of an attempted transition from a supported divide-by-2 mode to an unsupported divide-by-4 mode, the device will remain in divide-by-2 mode. In all cases, the HID1[PC0-5] bits will correctly reflect the current bus-to-core frequency multiplier.

Table 17. Document Revision History (continued)

Revision	Date	Substantive Change(s)
2		Table 6: Added separate input leakage specification for BVSEL0, $\overline{\text{LSSD\_MODE}}$, $\overline{\text{TCK}}$, TDI, TMS, $\overline{\text{TRST}}$ signals to correctly indicate leakage current for signals with internal pull-up resistors. Section 5.1: Added paragraph preceding Table 7 and edited notes in Table 7 to clarify core frequencies at which power consumption is measured. Section 5.3: Removed voltage derating specifications; this feature has been made redundant by new device offerings and is no longer supported. Changed names of “Typical–Nominal” and “Typical–Thermal” power consumption parameters to “Typical” and “Thermal”, respectively. (Name change only–no specifications were changed.) Table 11: Revised Notes 16, 18, and 19 to reflect current recommendations for connection of SENSE pins. Section 9.3: Added paragraph explaining connection recommendations for SENSE pins. (See also Table 11 entry above.) Table 19: Updated table to reflect changes in specifications for MC7448xxnnnnNC devices. Table 9: Changed all instances of TT[0:3] to TT[0:4] Removed mention of these input signals from output valid times and output hold times: • AACK, CKSTP_IN, DT[0:3] Figure 17: Modified diagram slightly to correctly show constraint on SYSCLK ramping is related to V_{DD} voltage, not AV_{DD} voltage. (Diagram clarification only; no change in power sequencing requirements.) Added Table 20 to reflect introduction of extended temperature devices and associated hardware specification addendum.
1		Added 1600 MHz, 1420 MHz, and 1000 MHz devices Section 4: corrected die size Table 2: Revised Note 4 to consider overshoot/undershoot and combined with Note 5. Table 4: Revised operating voltage for 1700 MHz device from ± 50 mV to +20 mV / –50 mV. Table 7: Updated and expanded table to include Typical – Nominal power consumption. Table 11: Added voltage derating information for 1700 MHz devices; this feature is not supported at this time for other speed grades. Added transient specifications for VDD power supply in Section 9.2.3, added Table 15 and Figure 19 and renumbered subsequent tables and figures. Moved Decoupling Recommendations from Section 9.4 to Section 9.2.4 and renumbered subsequent sections. Section 9.2.1: Revised power sequencing requirements. Section 9.7.4: Added thermal diode ideality factor information (previously TBD). Table 17: Expanded table to show HID1 register values when DFS modes are enabled. Section 11.2: updated to include additional N-spec device speed grades Tables 18 and 19: corrected PVR values and added “MC” product code prefix
0		Initial public release.